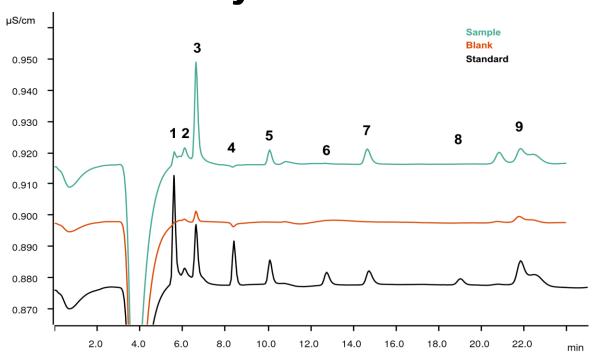
Anionic impurities in concentrated semiconductor grade ammonium hydroxide



Ultrapure chemicals are required to be applied in semiconductor industry. Ionic impurities may lead to compromised products. This application describes the determination of anionic impurities in semiconductor grade 28% ammonium hydroxide solution. To avoid matrix disturbances Inline Neutralization and Inline Preconcentration with Matrix Elimination needs to be applied.

Results

| Anion | Conc. [µg/L] | RSD [%, n = 6] | Anion | Conc. [µg/L] | RSD [%, n = 6] |
|------------|-----------------|-------------------|-------------|-----------------|-------------------|
| 1 Fluoride | 1.8 | 2.1 | 6 Bromide | n.d. | - |
| 2 Acetate | 11.1 | 13.7 | 7 Nitrate | 20.8 | 2.6 |
| 3 Formate | 56.7 | 2.9 | 8 Phosphate | n.d. | - |
| 4 Chloride | n.d. | - | 9 Sulfate | 7.9 | 5.5 |
| 5 Nitrite | 11.7 | 0.6 | | | |

Standard in graph: acetate, formate 8 µg/L each, all others 4 µg/L each



Sample

Semiconductor grade ammonium hydroxide (28%)

Sample preparation

Dilution 1:5 with ultrapure water, Metrohm Inline Neutralization with subsequent Metrohm Inline Preconcentration technique with Matrix Elimination (MiPCT-ME).

Columns

| Metrosep A Supp 5 - 250/4.0 | 6.1006.530 |
|-----------------------------|------------|
| Metrosep A Supp 5 Guard/4.0 | 6.1006.500 |
| Metrosep A PCC 2 HC/4.0 | 6.1006.340 |
| Metrosep I Trap 1 - 100/4.0 | 6.1017.200 |

Solutions

| Eluent (1:40) | concentrate | 128 mmol/L sodium carbonate 40 mmol/L sodium hydrogen carbonate | |
|------------------|-------------|---|--|
| Eluent | | 3.2 mmol/L sodium carbonate 1.0 mmol/L sodium hydrogen carbonate | |
| Suppressor | regenerant | 100 mmol/L sulfuric acid | |
| Rinsing solution | | STREAM | |
| SPM regenerant | | 100 mmol/L perchloric acid | |
| SPM rinsing | | Ultrapure water | |

Parameters

| Flow rate | 0.8 mL/min |
|-------------------------|------------|
| Preconcentration volume | 100 μL |
| P _{max} | 15 MPa |
| Recording time | 25 min |
| | |

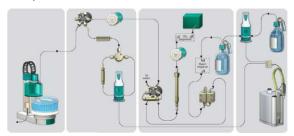
Analysis

Conductivity detection after sequential suppression

Instrumentation

| 940 Professional IC Vario ONE/SeS/PP/Prep 3 | 2.940.1530 |
|--|------------|
| IC Conductivity Detector | 2.850.9010 |
| 858 Professional Sample Processor | 2.858.0030 |
| 941 Eluent Production Module | 2.941.0010 |
| 800 Dosino | 2.800.0010 |
| ELGA PURELAB flex 5/6 | - |
| IC equipment: MiPT | 6.5330.180 |
| Sample rack 3 x 60.6 mm and 35 x 41 mm | 6.9920.191 |
| MSM Rotor A | 6.2832.000 |
| Adapter sleeve for Suppressor Vario | 6.2842.020 |
| SPM Rotor A | 6.2835.000 |
| 20 x PE bottle, 50 mL | 6.1608.100 |
| 20 x Septum screw cap | 6.1627.100 |
| Sample needle MF 1/16 in. | 6.2624.200 |
| Needle/tube holder 1/16 in. | 6.2833.010 |

Setup scheme



Remarks

The use of the ELGA PURELAB flex 5/6 with its direct ultrapure water supply is a prerequisite to achieve the required very low blank values. The preconcentration of 20 μL of the undiluted sample instead of 100 μL of the 1:5 dilution shows the same results.

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